

Search Notes

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Examiner

Hieu P. Nguyen

Applicant(s)/Patent under
Reexamination

OOYA ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	278-279	9/11/2007	HN
330	285	9/11/2007	HN
330	295	9/11/2007	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
US-PGPUB		9/11/2007	HN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST UPDATE SEARCH	9/11/2007	HN